## Notice of References Cited Application/Control No. 09/592,791 Examiner Devona E. Faulk Applicant(s)/Patent Under Reexamination WATANABE, KEITA Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-5,392,455	02-1995	Benoist et al.	340/7.62
*	В	US-5,861,686	01-1999	Lee, Jong Bae	310/36
*	С	US-4,115,770	09-1978	Kanazawa, Masayuki	340/392.3
*	D	US-5,668,423	09-1997	You et al.	310/81
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	4	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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